Approved For Release 2008/07/31 : CIA-RDP78B04555A000100100010-8

SECRET

OUT-67609

1969 MAY 6 23 56Z

S E C R E T 062346Z MAY 69 CITE [redacted] 6249 25X1
[redacted] 25X1

SUBJECT: YAW SLIT SMEAR

1. METHOD OF MEASURING YAW SLITS

A. ZERO COMPARATOR ON MAJOR IMAGE POINT A. THE X, Y CO-ORDINATES OF POINT A WILL NOT BE RECORDED.

B. MOVE TO MINOR IMAGE POINT B AND RECORD X, Y CO-ORDINATES.

C. YAW SLIT AREAS TO BE MEASURED WILL BE SELECTED IN ACCORDANCE WITH THAT INDICATED IN REFERENCE CABLE.

2. ALL DATA WILL BE RECORDED ON CARDS AND SENT TO [redacted] FOR [redacted] WITH INFO COPY TO [redacted] FOR PET MEETING. 25X1 25X1

3. CARD FORMAT, EFFECTIVE IMMEDIATELY, WILL BE AS FOLLOWS:

COL. 1-4	MISSION NUMBER
COL. 8-10	REV NUMBER RIGHT JUSTIFIED
COL. 12-14	FRAME NUMBER RIGHT JUSTIFIED
COL. 16	SMEAR SLIT IDENTIFIER ONE INDICATES DATA TRACK SIDE TWO INDICATES TITLE SIDE
COL. 21-23	APPROXIMATE TIME FROM START OF FRAME TO MEASURED AREA TO THE NEAREST TENTH OF A SECOND.
COL. 31	SIGN
COL. 32-34	X VALUE (ACROSS TRACK) IN MICRONS (PLUS TOWARD TIME DATA TRACK)
COL. 41	SIGN
COL. 42-44	Y VALUE (ALONG TRACK) IN MICRONS (PLUS TOWARD START OF FRAME)

S E C R E T

--END OF MESSAGE--

DISTRIBUTION		
	ARTICE	PI
1	FILE	
	CABLE SEC.	
	FP&B/RD	
	SECUR.	
2,3	TSSG/APSD	✓
	PSG/OC	
	RRD	
	REPRO	
	AID	
	IEG	
	PROD	
	SCIEN	
	WEST	
	EAST	
	M&S	
	PGM	
	IAS	
	DIA-XX4	
	SPAD	
	DIA-AP	
	[redacted]	
	CMX	

25X1

SECRET

ADVANCE CY SANITIZED WITH TEXT

GROUP 1 Excluded from automatic downgrading and declassification

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